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- Independent Registers for A and B Buses
- Multiplexed Real-Time and Stored Data
- Choice of True or Inverting Data Paths
- Choice of 3-State or Open-Collector Outputs
- Package Options Include Plastic Small-Outline (DW) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (NT) and Ceramic (JT) 300-mil DIPs

DEVICE	OUTPUT	LOGIC
SN54ALS646, SN74ALS646A, 'AS646	3 state	True
SN54ALS648, SN74ALS648A, SN74AS648	3 state	Inverting

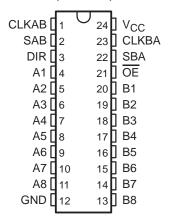
description

These devices consist of bus-transceiver circuits with 3-state or open-collector outputs, D-type flip-flops, and control circuitry arranged for multiplexed transmission of data directly from the data bus or from the internal storage registers. Data on the A or B bus is clocked into the registers on the low-to-high transition of the appropriate clock (CLKAB or CLKBA) input. Figure 1 illustrates the four fundamental bus-management functions that can be performed with the octal bus transceivers and registers.

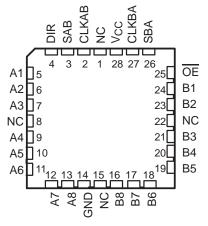
Output-enable (OE) and direction-control (DIR) inputs control the transceiver functions. In the transceiver mode, data present at the high-impedance port may be stored in either or both registers.

The select-control (SAB and SBA) inputs can multiplex stored and real-time (transparent mode)

SN54ALS646, SN54ALS648, SN54AS646 . . . JT PACKAGE SN74ALS646A, SN74ALS648A, SN74AS646, SN74AS648 . . . DW OR NT PACKAGE (TOP VIEW)



SN54ALS646, SN54ALS648, SN54AS646 . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

data. The circuitry used for select control eliminates the typical decoding glitch that occurs in a multiplexer during the transition between stored and real-time data. DIR determines which bus receives data when \overline{OE} is low. In the isolation mode (\overline{OE} high), A data may be stored in one register and/or B data may be stored in the other register.

When an output function is disabled, the input function is still enabled and can be used to store and transmit data. Only one of the two buses, A or B, may be driven at a time.

The -1 version of the SN74ALS646A is identical to the standard version, except that the recommended maximum I_{OL} in the -1 version is increased to 48 mA. There are no -1 versions of the SN54ALS646, SN54ALS648, or SN74ALS648A.

The SN54ALS646, SN54ALS648, and SN54AS646 are characterized for operation over the full military temperature range of –55°C to 125°C. The SN74ALS646A, SN74ALS648A, SN74AS646, and SN74AS648 are characterized for operation from 0°C to 70°C.

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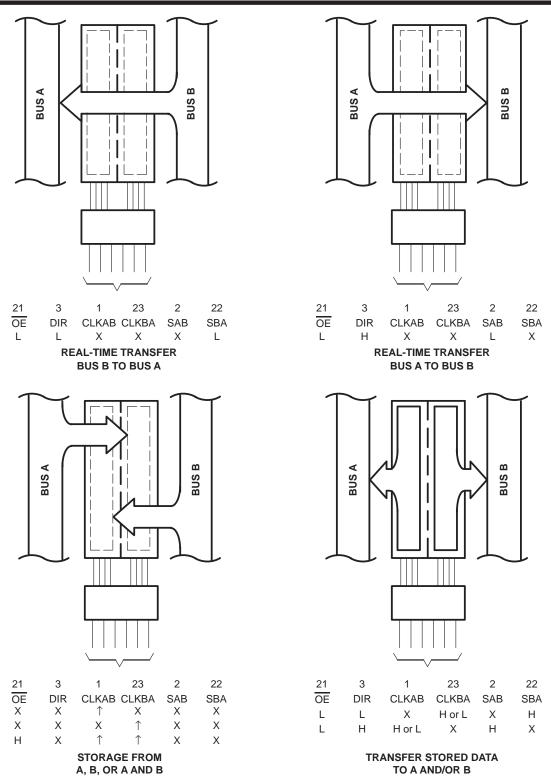


Figure 1. Bus-Management Functions

Pin numbers shown are for the DW, JT, and NT packages.



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Function Tables

SN54ALS646, SN54AS646, SN74ALS646A, SN74AS646

		INP	UTS			DAT	A I/O	OPERATION OR FUNCTION
ŌĒ	DIR	CLKAB	CLKBA	SAB	SBA	A1-A8	B1-B8	OPERATION OR FUNCTION
Х	Х	1	X	Х	Х	Input	Unspecified [†]	Store A, B unspecified [†]
Х	Χ	Χ	\uparrow	Χ	Χ	Unspecified [†]	Input	Store B, A unspecified [†]
Н	Х	1	↑	Х	Х	Input	Input	Store A and B data
Н	Х	H or L	H or L	Χ	Χ	Input disabled	Input disabled	Isolation, hold storage
L	L	Χ	Χ	Χ	L	Output	Input	Real-time B data to A bus
L	L	Χ	H or L	Χ	Н	Output	Input	Stored B data to A bus
L	Н	Х	Х	L	Х	Input	Output	Real-time A data to B bus
L	Н	H or L	Χ	Н	Χ	Input	Output	Stored A data to B bus

[†] The data output functions can be enabled or disabled by various signals at $\overline{\text{OE}}$ and DIR. Data input functions are always enabled; i.e., data at the bus terminals is stored on every low-to-high transition of the clock inputs.

SN54ALS648, SN74ALS648A, SN74AS648

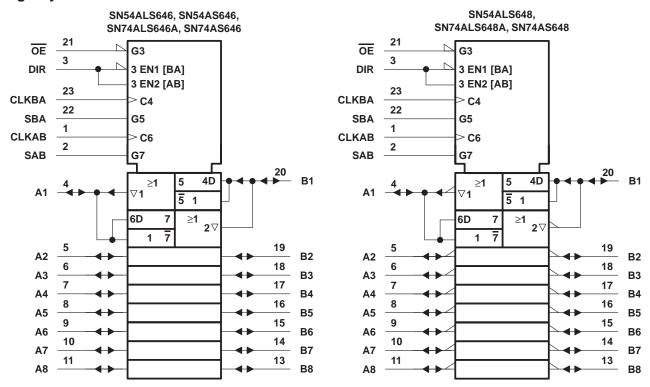
		INP	UTS			DAT	A I/O	OPERATION OR FUNCTION					
OE	DIR	CLKAB	CLKBA	SAB	SBA	A1-A8	B1-B8	OPERATION OR FUNCTION					
Х	Х	↑	Х	Χ	Χ	Input	Unspecified [†]	Store A, B unspecified [†]					
X	X	Χ	\uparrow	Χ	Χ	Unspecified [†]	Input	Store B, A unspecified [†]					
Н	Х	1	1	Χ	Х	Input	Input	Store A and B data					
Н	X	H or L	H or L	Χ	Χ	Input disabled	Input disabled	Isolation, hold storage					
L	L	Х	Х	Χ	L	Output	Input	Real-time \overline{B} data to A bus					
L	L	Χ	H or L	Χ	Н	Output	Input	Stored \overline{B} data to A bus					
L	Н	Х	Х	L	Х	Input	Output	Real-time A data to B bus					
L	Н	H or L	Χ	Н	Χ	Input	Output	Stored \overline{A} data to B bus					

[†] The data output functions can be enabled or disabled by various signals at OE and DIR. Data input functions are always enabled; i.e., data at the bus terminals is stored on every low-to-high transition of the clock inputs.



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logic symbols†

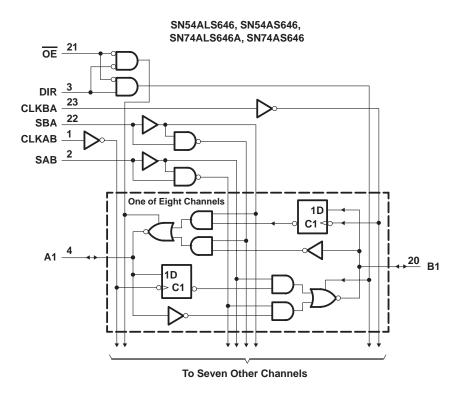


[†] These symbols are in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for the DW, JT, and NT packages.



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logic diagrams (positive logic)



SN54ALS648, SN74AS648 OE DIR SBA 22 CLKBA SBA SBA 22 CLKAB To Seven Other Channels

Pin numbers shown are for the DW, JT, and NT packages.



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V _{CC}	
Input voltage, V _I : Control inputs	
I/O ports 5.5 V	
Operating free-air temperature range, T _A : SN54ALS646 –55°C to 125°C	
SN74ALS646A 0°C to 70°C	
Storage temperature range –65°C to 150°C	

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

		SN	54ALS6	46	SN7	'4ALS64	6A	UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
VCC	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
V _{IH}	High-level input voltage	2			2			V
V _{IL}	Low-level input voltage			0.7			0.8	V
loh	High-level output current			-12			-15	mA
Ī	Low-level output current			12			24	0
lOL							48‡	mA
fclock	Clock frequency	0		35	0		40	MHz
t _W	Pulse duration, CLKBA or CLKAB high or low	14.5			12.5			ns
t _{su}	Setup time, A before CLKAB↑ or B before CLKBA↑	15			10			ns
th	Hold time, A after CLKAB↑ or B after CLKBA↑	0			0			ns
TA	Operating free-air temperature	-55		125	0		70	°C

 $[\]ddagger$ Applies only to the -1 version and only if V_{CC} is maintained between 4.75 V and 5.25



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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CO	NDITIONS	SN	54ALS6	46	SN7	4ALS64	6A	UNIT
	PARAMETER	1251 CO	NUTTIONS	MIN	TYP [†]	MAX	MIN	TYP [†]	MAX	UNIT
٧ıK		V _{CC} = 4.5 V,	$I_{I} = -18 \text{ mA}$			-1.2			-1.2	V
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V},$	$I_{OH} = -0.4 \text{ mA}$	V _{CC} -2			V _{CC} -2			
\ _{\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\}			$I_{OH} = -3 \text{ mA}$	2.4	3.2		2.4	3.2] ,
VOH		V _{CC} = 4.5 V	$I_{OH} = -12 \text{ mA}$	2						V
			$I_{OH} = -15 \text{ mA}$				2			
			I _{OL} = 12 mA		0.25	0.4		0.25	0.4	
VOL		V _{CC} = 4.5 V	$I_{OL} = 24 \text{ mA}$					0.35	0.5	V
			$I_{OL} = 48 \text{ mA}^{\ddagger}$					0.35	0.5	
	Control inputs	V _{CC} = 5.5 V	V _I = 7 V			0.1			0.1	mA
ΙΙ	A or B ports	VCC = 3.3 V	V _I = 5.5 V			0.1			0.1	ША
	Control inputs	V 55V	V. 27V			20			20	4
ΙΗ	A or B ports§	V _{CC} = 5.5 V,	V _I = 2.7 V			20			20	μΑ
Γ.	Control inputs	V 55V				-0.2			-0.2	4
¹IL	A or B ports§	V _{CC} = 5.5 V,	V _I = 0.4 V			-0.2			-0.2	mA
IO¶	-	V _{CC} = 5.5 V,	V _O = 2.25 V	-20		-112	-30		-112	mA
			Outputs high		47	76		47	76	
Icc	V	V _{CC} = 5.5 V	Outputs low		55	88		55	88	mA
			Outputs disabled		55	88		55	88	

 $^{^\}dagger$ All typical values are at VCC = 5 V, TA = 25°C. † Applies only to the -1 version and only if VCC is maintained between 4.75 V and 5.25 § For I/O ports, the parameters I $_{\rm IH}$ and I $_{\rm IL}$ include the off-state output current.

The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, IOS.

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _C C _L R1 R2 T _A	UNIT			
			SN54A	LS646	SN74AL	S646A	
			MIN	MAX	MIN	MAX	
f _{max}			35		40		MHz
^t PLH	CLKBA or CLKAB	A or B	10	35	7	30	ns
t _{PHL}	CENDA OF CENAD	AOID	5	20	5	17	115
^t PLH	A or B	B or A	5	22	3	20	ns
^t PHL	AOID	DOIA	3	15	3	12	113
^t PLH	SBA or SAB‡	A or B	10	40	7	35	ns
^t PHL	(stored data low)	(stored data low)	5	23	5	20	115
^t PLH	SBA or SAB [‡]	A or B	8	30	6	25	200
t _{PHL}	(stored data high)	AUIB	5	24	5	20	ns
^t PZH	ŌĒ	A or B	3	20	2	17	ns
^t PZL	OE	AOIB	5	22	4	20	115
^t PHZ	ŌĒ	A or B	1	12	1	10	ns
tPLZ	OE	AUIB	1	20	2	16	115
^t PZH	DIR	A or B	5	38	3	30	ns
t _{PZL}	DIK	A OLB	5	30	4	25	119
^t PHZ	DIR	A or B	1	12	1	10	ne
^t PLZ	DIK	AUB	2	21	2	16	ns

[†] For conditions shown MIN or MAX, use the appropriate value specified under recommended operating conditions. ‡ These parameters are measured with the internal output state of the storage register opposite that of the bus input.

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V_{CC} I/O ports 5.5 V Operating free-air temperature range, T_A: SN54ALS648 –55°C to 125°C

recommended operating conditions

		SN	54ALS6	48	SN7	'4ALS64	8A	UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	ONT
VCC	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
V_{IH}	High-level input voltage	2			2			V
V_{IL}	Low-level input voltage			0.7			0.8	V
loh	High-level output current			-12			-15	mA
lOL	Low-level output current			12			24	mA
f _{clock}	Clock frequency	0		35	0		40	MHz
t _W	Pulse duration, CLKBA or CLKAB high or low	14.5			12.5			ns
t _{su}	Setup time, A before CLKAB↑ or B before CLKBA↑	15			10			ns
th	Hold time, A after CLKAB↑ or B after CLKBA↑	0			0			ns
TA	Operating free-air temperature	-55		125	0		70	°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	DADAMETED	TEST CO	NDITIONS	SN	54ALS6	48	SN7	'4ALS64	8A	UNIT
	PARAMETER	TEST CO	NDITIONS	MIN	TYP [†]	MAX	MIN	TYP [†]	MAX	UNII
VIK		$V_{CC} = 4.5 \text{ V},$	$I_{I} = -18 \text{ mA}$			-1.2			-1.2	V
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V},$	$I_{OH} = -0.4 \text{ mA}$	V _{CC} -2			V _{CC} -2			
\/a			$I_{OH} = -3 \text{ mA}$	2.4	3.2		2.4	3.2		V
VOH		V _{CC} = 4.5 V	$I_{OH} = -12 \text{ mA}$	2						V
			$I_{OH} = -15 \text{ mA}$				2			
\/o.	V _{CC} = 4.5 V		I _{OL} = 12 mA		0.25	0.4		0.25	0.4	V
VOL		VCC = 4.5 V	I _{OL} = 24 mA					0.35	0.5	V
١.	Control inputs	V _{CC} = 5.5 V	V _I = 7 V			0.1			0.1	mA
Ħ	A or B ports		V _I = 5.5 V			0.1			0.1	ША
	Control inputs	F.F.V	V. 97V			20			20	
ΊΗ	A or B ports [‡]	V _{CC} = 5.5 V,	V _I = 2.7 V			20			20	μΑ
	Control inputs	V 55V				-0.2			-0.2	
ΊL	A or B ports‡	V _{CC} = 5.5 V,	V _I = 0.4 V			-0.2			-0.2	mA
ΙΟ§		V _{CC} = 5.5 V,	V _O = 2.25 V	-20		-112	-30		-112	mA
			Outputs high		47	76		47	76	
ICC	V	V _{CC} = 5.5 V	Outputs low		57	88		57	88	mA
			Outputs disabled		57	88		57	88	

[†] All typical values are at V_{CC} = 5 V, T_A = 25°C. ‡ For I/O ports, the parameters I_{IH} and I_{IL} include the off-state output current.

[§] The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, Ios.

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PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _C C _L R1 R2 T _A	UNIT			
			SN54A	LS648	SN74AL	S648A	
			MIN	MAX	MIN	MAX	
f _{max}			35		40		MHz
^t PLH	CLKBA or CLKAB	A or B	8	39	7	33	ns
^t PHL	CERBA OF CERAB	AOIB	5	23	5	20	115
^t PLH	A or B	B or A	3	20	2	17	ns
^t PHL	AOIB	BOIA	2	12	2	10	115
^t PLH	SBA or SAB‡	A or B	5	44	5	39	ns
^t PHL	(stored data low)	AOIB	4	26	4	22	115
^t PLH	SBA or SAB‡	A or B	6	30	6	25	ne
^t PHL	(stored data high)	AUIB	6	25	6	21	ns
^t PZH	ŌĒ	A or B	4	25	2	22	ns
t _{PZL}	T OE	AOIB	4	25	4	22	115
^t PHZ	ŌĒ	A or B	1	12	1	10	ns
^t PLZ	T OE	AOIB	2	21	2	15	ns
^t PZH	DIR	A or B	4	35	2	27	
t _{PZL}	אוע	AUID	3	25	3	19	ns
^t PHZ	DIR	A or B	1	17	1	14	
^t PLZ		AOIB	2	22	2	15	ns

[†] For conditions shown MIN or MAX, use the appropriate value specified under recommended operating conditions.

[‡] These parameters are measured with the internal output state of the storage register opposite that of the bus input.

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V _{CC}	
Input voltage, V _I : Control inputs	$\dots \dots $
I/O ports	
Operating free-air temperature range, T _A : SN54AS646	55°C to 125°C
SN74AS646	0°C to 70°C
Storage temperature range	-65° C to 150° C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

			SI	N54AS64	ŀ6	SN	174AS64	6	UNIT
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT
VCC	Supply voltage		4.5	5	5.5	4.5	5	5.5	V
V_{IH}	High-level input voltage					2			V
V _{IL}	Low-level input voltage				0.8			0.8	V
lOH	High-level output current				-12			-15	mA
lOL	Low-level output current				32			48	mA
fclock*	Clock frequency		0		75	0		90	MHz
4 *	Pulse duration	CLKBA or CLKAB high	6			5			20
t _W *	Fulse duration	CLKBA or CLKAB low	7			6			ns
t _{su} *	Setup time, A before CLKAB↑ or B before CLKBA↑		7			6			ns
th*	Hold time, A after CLKAB↑ or B before CLKBA		0			0			ns
TA	Operating free-air temperature		-55		125	0		70	°C

^{*} On products compliant to MIL-STD-883, Class B, this parameter is based on characterization data but is not production tested.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST 00	TEST CONDITIONS		SN54AS646		SN74AS646			UNIT	
	PARAMETER	lESI CO	NUTTIONS	MIN	TYP [†]	MAX	MIN	TYP [†]	MAX	UNII	
VIK		V _{CC} = 4.5 V,	I _I = -18 mA			-1.2			-1.2	V	
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V},$	$I_{OH} = -2 \text{ mA}$	V _{CC} -2			V _{CC} -2				
,			$I_{OH} = -3 \text{ mA}$	2.4	3.2		2.4	3.2		V	
VOH		V _{CC} = 4.5 V	$I_{OH} = -12 \text{ mA}$	2							
			$I_{OH} = -15 \text{ mA}$				2				
\/0.	V _{CC} = 4.5 V		I _{OL} = 32 mA		0.25	0.5				V	
VOL		VCC = 4.5 V	$I_{OL} = 48 \text{ mA}$					0.35	0.5	v	
١.	Control inputs	V _{CC} = 5.5 V,	V _I = 7 V			0.1			0.1	mA	
ΙΙ	A or B ports	$V_{CC} = 5.5 \text{ V},$	V _I = 5.5 V			0.1			0.1		
	Control inputs	V	V 07V			20			20		
ΊΗ	A or B ports [‡]	V _{CC} = 5.5 V,	V _I = 2.7 V			70			70	μΑ	
Γ.	Control input	V	V 04V			-0.5			-0.5	A	
IIL	A or B ports‡	$V_{CC} = 5.5 \text{ V},$	V _I = 0.4 V			-0.75			-0.75	mA	
IO§		V _{CC} = 5.5 V,	V _O = 2.25 V	-30		-112	-30		-112	mA	
			Outputs high		120	195		120	195	mA	
ICC		V _{CC} = 5.5 V	Outputs low		130	211		130	211		
			Outputs disabled		130	211		130	211		

 $[\]overline{\dagger}$ All typical values are at $V_{CC} = 5$ V, $T_A = 25$ °C.

[‡] For I/O ports, the parameters I_{IH} and I_{IL} include the off-state output current. § The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, I_{OS}.

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PARAMETER	FROM (INPUT)	TO (OUTPUT)	V_{CC} = 4.5 V to 5.5 V, C_L = 50 pF, $R1$ = 500 Ω , $R2$ = 500 Ω , T_A = MIN to MAX †				UNIT
			SN54AS646		SN74AS646		
			MIN	MAX	MIN	MAX	
f _{max} *			75		90		MHz
^t PLH	CLKBA or CLKAB	A or B	2	9.5	2	8.5	ns
^t PHL		AUD	2	10	2	9	115
t _{PLH}	A or B	B or A	2	11.5	2	9	ns
^t PHL		DOLA	1	8	1	7	115
^t PLH	SBA or SAB‡	A or B	2	13.5	2	11	ns
^t PHL	SBA OF SAB+	A 01 B	2	11	2	9	115
^t PZH	ŌĒ	A or B	2	11	2	9	ns
t _{PZL}	OE	AUIB	3	15	3	14	115
^t PHZ	ŌĒ	A or B	2	11	2	9	ns
t _{PLZ}	OE	AUD	2	11	2	9	115
^t PZH	DIR	A or B	3	21	3	16	ns
t _{PZL}		7010	3	24	3	18	110
^t PHZ	DIR	A or B	2	12	2	10	ns
^t PLZ	DIK	AOIB	2	12	2	10	115

^{*} On products compliant to MIL-STD-883, Class B, this parameter is based on characterization data but is not production tested.

[†] For conditions shown MIN or MAX, use the appropriate value specified under recommended operating conditions.

[‡]These parameters are measured with the internal output state of the storage register opposite that of the bus input.

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V _{CC}	V
Input voltage, V _I : Control inputs 7	V
I/O ports 5.5	٧
Operating free-air temperature range, T _A : SN74AS648	C
Storage temperature range ——65°C to 150°	C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

			SN74AS648			UNIT
			MIN	NOM	MAX	UNIT
VCC	CC Supply voltage			5	5.5	V
V _{IH}	High-level input voltage		2			V
V _{IL}	Low-level input voltage				0.8	V
loh	High-level output current				-15	mA
lOL	Low-level output current				48	mA
fclock	Clock frequency		0		90	MHz
	Pulse duration CLKBA or	CLKBA or CLKAB high	5			ns
t _W	r dise duration	CLKBA or CLKAB low	6			115
t _{su}	Setup time, A before CLKAB↑ or B before CLKBA↑		6			ns
t _h	Hold time, A after CLKAB↑ or B before CLKBA		0			ns
TA	Operating free-air temperature		0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST COMPITIONS		SN	SN74AS648		
		TEST CONDITIONS			TYP [‡]	MAX	UNIT
VIK		V _{CC} = 4.5 V,	I _I = –18 mA			-1.2	V
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V},$	I _{OH} = -2 mA	V _{CC} -2			
Vон		V 45V	I _{OH} = −3 mA	2.4	3.2		V
		V _{CC} = 4.5 V	I _{OH} = -15 mA	2			
VOL		V _{CC} = 4.5 V,	I _{OL} = 48 mA		0.35	0.5	V
ı.	Control inputs	Van EEV	V _I = 7 V			0.1	mA
1 ₁	A or B ports	$V_{CC} = 5.5 V$	V _I = 5.5 V			0.1 m <i>F</i>	MA
	Control inputs	.,	V 07V			20	•
lН	A or B ports§	$V_{CC} = 5.5 V$	V _I = 2.7 V			70	μΑ
	Control input					-0.5	
IIL	A or B ports§	$V_{CC} = 5.5 V$	$V_I = 0.4 V$			-0.75	mA
IOI		V _{CC} = 5.5 V,	V _O = 2.25 V	-30		-112	mA
			Outputs high		110	185	
ICC		$V_{CC} = 5.5 V$	Outputs low		120	195	mA
			Outputs disabled		120	195	

 $[\]ddagger$ All typical values are at V_{CC} = 5 V, T_A = 25 °C.

The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, IOS.



[§] For I/O ports, the parameters I_{IH} and I_{IL} include the off-state output current.

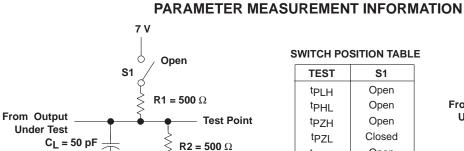
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PARAMETER	FROM (INPUT)	ТО (ОИТРИТ)	V _{CC} = 4.5 C _L = 50 pF R1 = 500 Ω R2 = 500 Ω T _A = MIN to	UNIT	
			SN74AS648		
			MIN	MAX	
fmax			90		MHz
t _{PLH}	CLKBA or CLKAB	A or B	2	8.5	ns
^t PHL		7010	2	9	115
^t PLH	A or B	B or A	2	8	
^t PHL			1	7	ns
^t PLH		A or B	2	11	ns
^t PHL	SBA or SAB‡	AUIB	2	9	115
^t PZH	ŌĒ	A or B	2	9	
t _{PZL}	OE	AUIB	3	15	ns
^t PHZ	ŌĒ	A or B	2	9	ns
^t PLZ	OE	A 01 B	2	9	115
^t PZH	DIR	A or B	3	16	nc
tPZL		A UI B	3	18	ns
^t PHZ	DIR	A or B	2	10	
^t PLZ	DIK	AUID	2	10	ns

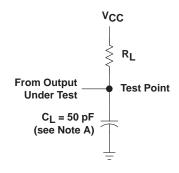
[†] For conditions shown MIN or MAX, use the appropriate value specified under recommended operating conditions.

[‡] These parameters are measured with the internal output state of the storage register opposite that of the bus input.

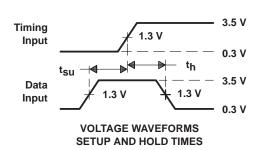
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Closed **t**PZL Open ^tPHZ t_{PLZ} Closed



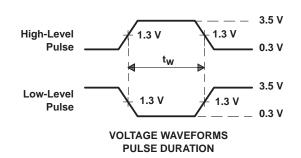
LOAD CIRCUIT FOR OPEN-COLLECTOR OUTPUTS

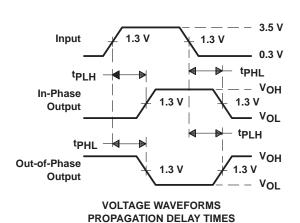


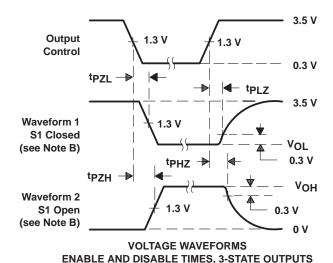
LOAD CIRCUIT

FOR 3-STATE OUTPUTS

(see Note A)







NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_{\Omega} = 50 \Omega$, $t_{r} \leq$ 2 ns, $t_{f} \leq$ 2 ns.
- D. The outputs are measured one at a time with one transition per measurement.

Figure 2. Load Circuits and Voltage Waveforms



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